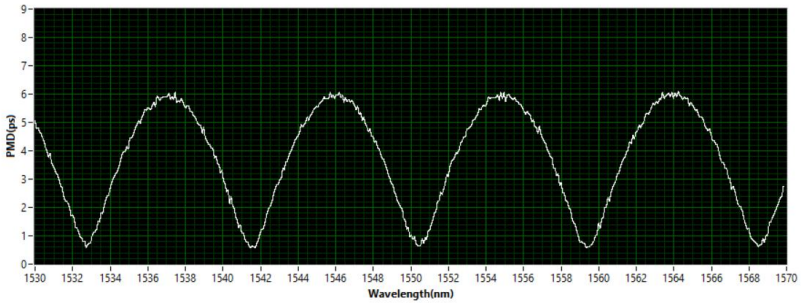
OCI-V Optical Vector Analysis System

Description

The OCI-V is an optical vector analysis system for loss, dispersion measurement of optical device. Its principle is based on linearly tunable laser and coherent detection technologies. By measuring the Jones matrix of DUT, insertion loss, dispersion, PDL, PMD can be calculated easily and precisely through OCI-V. Based on the unique optical design and the advanced algorithms, fast measurement and self-calibration are the advantages of this system, which makes it an ideal tool for optical vector measurement.

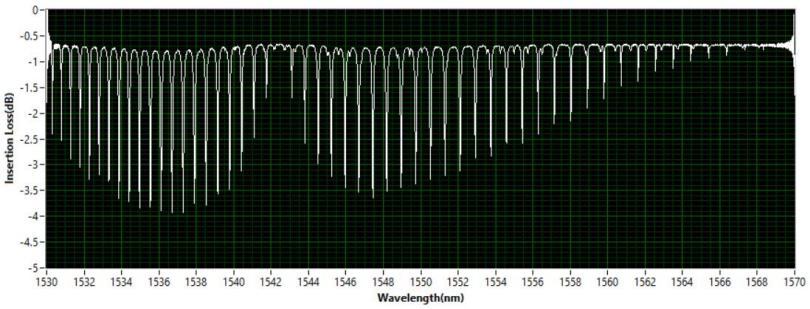
Features

- Measurement length: 200m
- Self-calibration
- Wavelength: C+L band, O-band
- Various optical parameters can be captured in one second



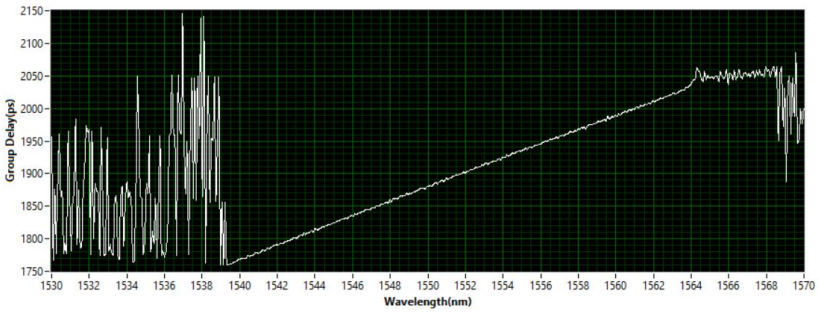
Applications

- Planar waveguide device
- Silicon photonics device
- Optical fiber device
- Optical adjustable device, amplifier, filter



Measurement Parameters

- Insertion loss
- Group delay
- Chromatic delay
- Polarization dependent loss
- Polarization mode dispersion
- Jones matrix



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Parameters

Parameters		
Measurement length	200	m
Wavelength	C+L band: 1525~1625；O band: 1265~1345	nm
Wavelength resolution	1.6	pm
Wavelength accuracy	±1.0	pm
Loss		
Dynamic range	60	dB
Insertion loss accuracy	±0.1	dB
Resolution	±0.05	dB
Group delay		
Range	6	ns
Accuracy	±0.2	ps
Loss rang	45	dB
Chromatic dispersion		
Accuracy	±10	ps/nm
PDL		
Dynamic range	40	dB
Accuracy	±0.05	dB
PMD		
Range	6	ns
Accuracy	±0.1	ps
Loss range	40	dB
Hardware		
Power	60	W
Communicaiton interface	USB	-
Optical fieber connector	FC/APC	-
Dimension	D 330 * W 350 * H 160	mm
Weight	7.5	kg
Storage temperature	0~50	℃
Operating temperature	10~40	℃
Relative humidity	10~90	%RH

ETSC Technologies Europe
Phone: + 32 472 611 456 Email: sales@etsc-tech.be Web: www.etsc-tech.be Add: Rue Laid Burniat 3, 1348 Louvain-la-Neuve, Begium